Amendments to the Claims

1. (*Currently Amended*) A test module for testing the susceptibility of an integrated circuit design to latch-up, the test module ~~comprising~~ comprising:

_____a plurality of test blocks ~~(30)~~, connected in parallel, each test block ~~comprising~~ including an injector block ~~(12)~~ for applying a stress current or voltage to the respective test block ~~(30)~~, and

_____a plurality of sensor blocks ~~(13)~~ located at successively increasing distances from the respective injector block ~~(12)~~, each sensor block ~~(13) comprising~~ including a PNPN latch-up test structure.

2. (*Currently Amended*) ~~A test module according to claim 1,~~ The test module as recited in claim 1, wherein each test block ~~(30)~~ is connected to a bondpad ~~(11)~~, said stress current or voltage being applied to said injector ~~(12)~~ via said bondpad ~~(11)~~.

3. (*Currently Amended*) ~~A test module according to claim 1 or claim 2,~~ The test module as recited in claim 1, wherein said injector blocks ~~(12)~~ are connected between first and second supply lines ~~(14,15)~~.

4. (*Currently Amended*) ~~A test module according to any one of claims 1 to 3,~~ The test module as recited in claim 1, wherein contacts ~~(5,6)~~ of said sensor blocks ~~(13)~~ are connected between third and fourth supply lines ~~(18,19)~~, different from said first and second supply lines ~~(14,15)~~.

5. (*Currently Amended*) ~~A test module according to any one of the preceding claims~~ The test module as recited in claim 1, wherein each PNPN latch-up structure ~~comprises~~ includes an N^+ and a P^+ hot-active ~~(7,8)~~, which hot-actives ~~(7,8)~~ are connected to respective probe sensor lines ~~(16,17)~~.

6. (*Currently Amended*) ~~A test module according to any one of the preceding claims,~~ The test module as recited in claim 1, wherein heating means ~~(20)~~ is provided in respect of said PNPN latch-up test structures.

7. (*Currently Amended*) A test module according to claim 6, wherein said heating means comprise polysilicon rings ~~(20)~~ located around respective PNPN latch-up test structures.

8. (*Currently Amended*) A method of testing the susceptibility of an integrated circuit design to latch-up, the method ~~comprising~~ comprising:

_____providing a test module comprising a plurality of test blocks ~~(30)~~, connected in parallel, each test block ~~(30) comprising~~ including,

_____an injector block ~~(12)~~ for applying a stress current or voltage to the respective test block ~~(30)~~, and

_____a plurality of sensor blocks ~~(13)~~ located at successively increasing distances from the respective injector block ~~(12)~~, each sensor block ~~(30) comprising~~ including a PNPN latch-up test structure,

_____~~the method further comprising~~ applying a stress current or voltage to one or more of the injector blocks ~~(12)~~, and

_____obtaining resultant current measurements at one or more of the respective sensor blocks ~~(13)~~.

9. (*Currently Amended*) ~~A method according to claim 8,~~ The method as recited in claim 8, further comprising,

_____disconnecting said sensor blocks ~~(13)~~ during application of said stress current or voltage to one or more of said injector blocks ~~(12)~~, and

_____obtaining current measurements at said injector blocks ~~(12)~~ to determine the susceptibility thereof to latch-up.

10. (*Currently Amended*) ~~A method according to claim 8 or claim 9,~~ The method as recited in claim 8, wherein an injector block ~~(12)~~ or a sensor block ~~(13)~~ is determined to

be susceptible to latch-up if a current measurement ~~thereat~~ therein exceeds a predetermined threshold.

11. (*Currently Amended*) ~~A method according to any one of claims 8 to 10,~~ The method as recited in claim 8, wherein sequential current measurements are obtained at each PNPN latch-up test structure of a sensor block ~~(13)~~.

12. (*Currently Amended*) ~~A method according to any one of claims 8 to 11,~~ The method as recited in claim 8, wherein each injector block ~~(12)~~ and each sensor block ~~(13)~~ can be independently biased.

13. (*Currently Amended*) ~~A method according to claim 12,~~ The method as recited in claim 12, wherein each PNPN latch-up test structure can be biased independently.